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Kevin Harding: 39 Years of Optics, Vision, Metrology Experience Editor/Primary Author CRC Handbook Optical Dimensional Metrology SPIE 30+ Years Chair, Instructor, Fellow, Past President, Pres. Award SME Young Engineer & Eli Whitney Award, Sr. Member, MVA Chair AIA Leadership Award, Engineering Society of Detroit Leadership Author >150 paper, 5 book chapters, >80 patents optics/metrology >80 Tutorials taught, Optics and Lighting for Machine Vision, Metrology, Optics for Non-Optics People, 3D ...

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Optical metrology for immersive display components and subsystems Proceedings of SPIE (May 21 2018) Dual mode snapshot interferometric system for on machine metrology (Conference...

Precision optical metrology of injection molds for ...

SPIE Digital Library Proceedings. In order to improve the efficiency of optical components for microlithography, metrology for comprehensive characterization of DUV and VUV radiation and the related optics has been developed at Laser-Laboratorium Gottingen.

Optical metrology in the VUV and EUV spectral range

DESCRIPTION Practical Optical Dimensional Metrology provides basic explanations of the operation and application of the most common methods in the field and in commercial use.

Practical Optical Dimensional Metrology

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A toolbox of metrology-based techniques for optical ... - SPIE

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Optical metrology: the long and unstoppable way to become ...

"Optical Technology and Measurement for Industrial Applications Conference", Proc. SPIE 11142, Optical Technology and Measurement for Industrial Applications Conference, 1114201 (21 April 2019); ... Overlay metrology simulations: analytical and experimental validations Proceedings of SPIE (June 02 2003) ...

Optical Technology and Measurement for Industrial ... - SPIE

Using key performance indicators (KPIs) and information produced by multiple optical measurement conditions, it is possible to optimize SEM sampling across the wafer and to capture all relevant target deformations.

Optical imaging metrology calibration using high ... - SPIE

Schott Glass is producing and developing the optical material for various specialized applications in photonics, optical and microlithography technology. In order to achieve the specifications several of metrology R&D activities have been done and hardware has been installed in the metrology labs.

Advanced industrial metrology used for ... - SPIE

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